

Notice of References Cited	Application/Control No. 10/591,433		Applicant(s)/Patent Under Reexamination IZUMI ET AL.	
	Examiner DWIN M. CRAIG		Art Unit 2123	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-7,020,598 B1	03-2006	Jacobson, Neil G.	703/14
*	C	US-5,805,608 A	09-1998	Baeg et al.	714/726
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*	E	US-4,517,154	05-1985	Dennis et al.	376/259
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*	G	US-6,691,079 B1	02-2004	Lai et al.	703/16
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Charles E. Stroud, Joe K. Tannehill, Jr., "Applying Build-In Self-Test to Majority Voting Fault Tolerant Circuits", IEEE, 1998, 6 pages.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.